

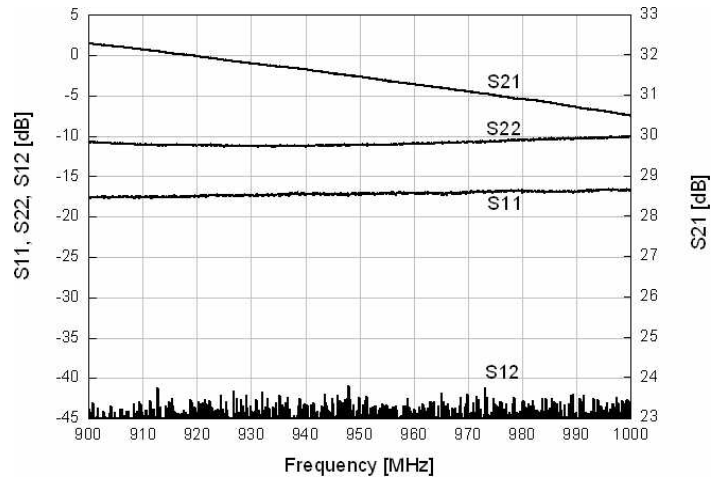
**Typical Performance
(Measured)**

Tx

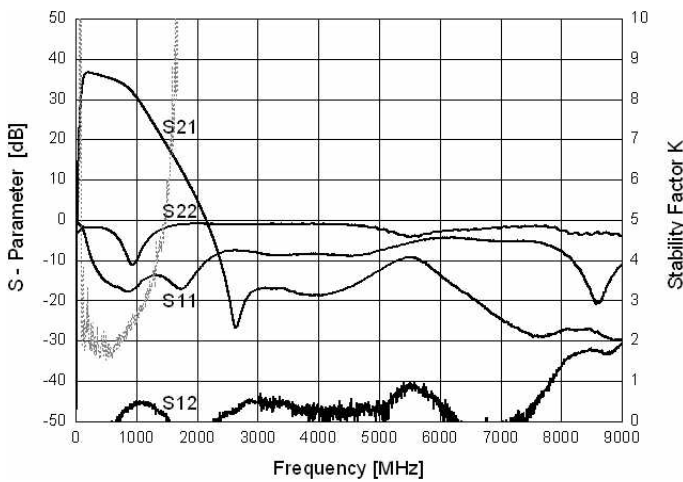
900~1000

+5 V

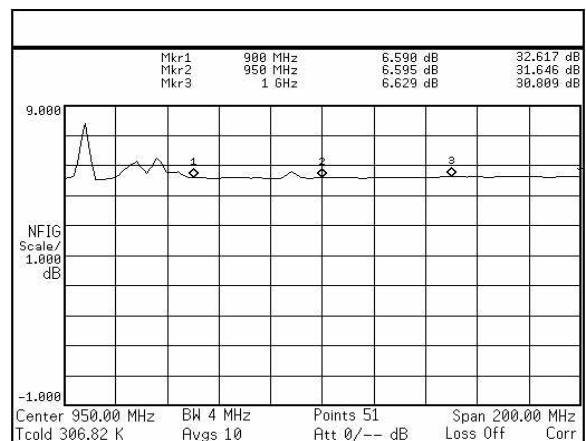
S-parameters



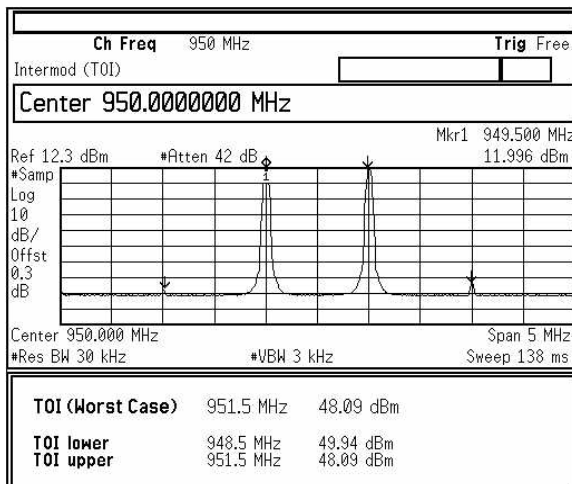
Stability Factor (K)



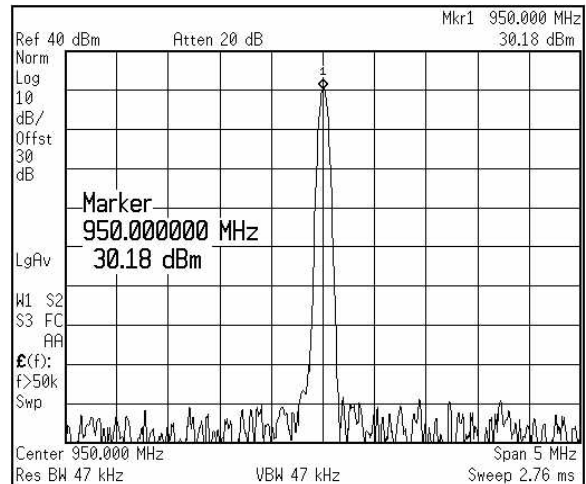
Noise Figure



OIP3

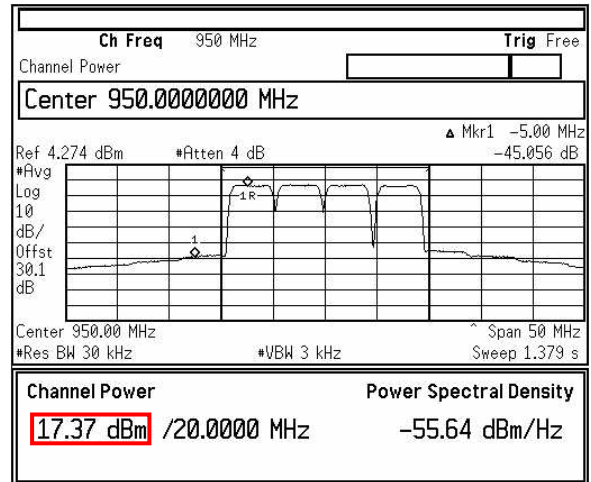
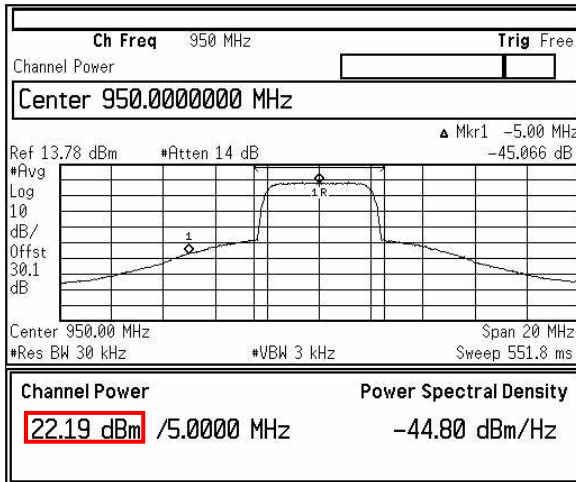


P1dB



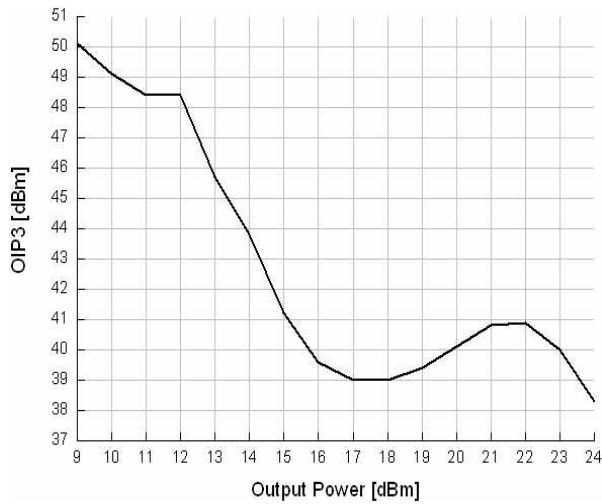
Output Channel Power

(@ ACLR=-45dBc, +/-5MHz Offset)

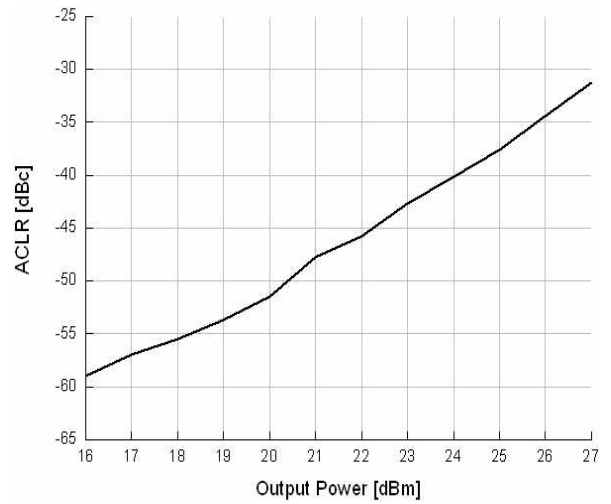


OIP3 vs Output Power

(@ 1MHz offset, 1-tone power)

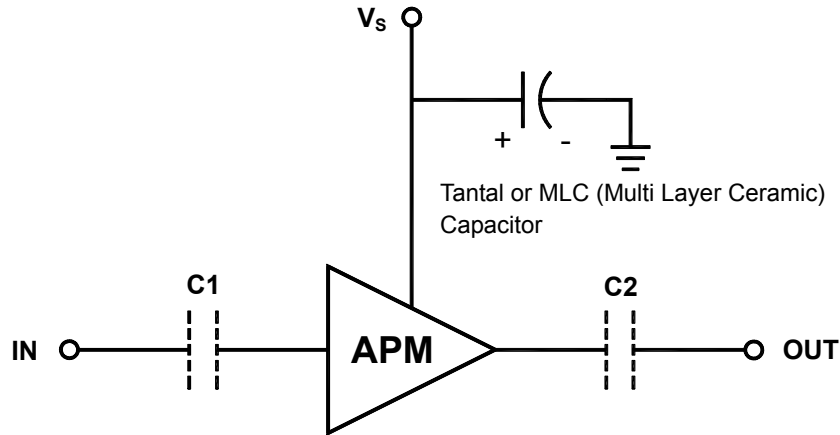


ACLR vs Channel Power



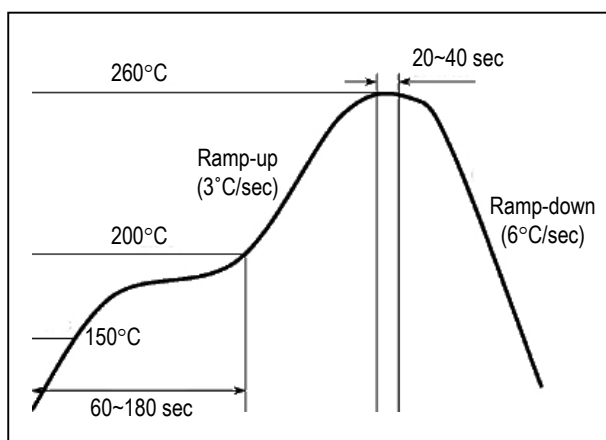
* Test Source : Agilent E4433B (3GPP W-CDMA Test Model-1 64DPCH)

Application Circuit

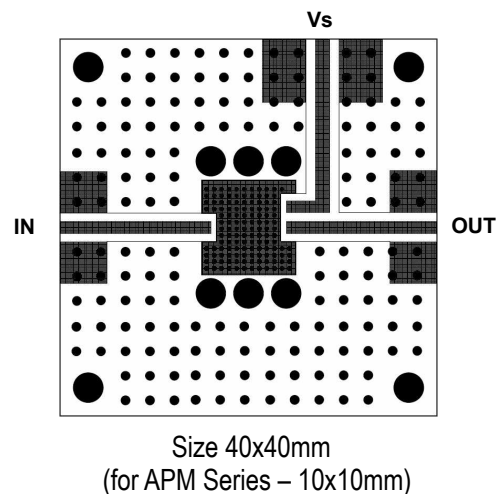


- 1) The tantalum or MLC (Multi Layer Ceramic) capacitor is optional and for bypassing the AC noise introduced from the DC supply. The capacitance value may be determined by customer's DC supply status. The capacitor should be placed as close as possible to V_s pin and be connected directly to the ground plane for the best electrical performance.
- 2) DC blocking capacitors are always necessarily placed at the input and output port for allowing only the RF signal to pass and blocking the DC component in the signal. The DC blocking capacitors are included inside the APM module. Therefore, C1 & C2 capacitors may not be necessary, but can be added just in case that the customer wants. The value of C1 & C2 is determined by considering the application frequency.

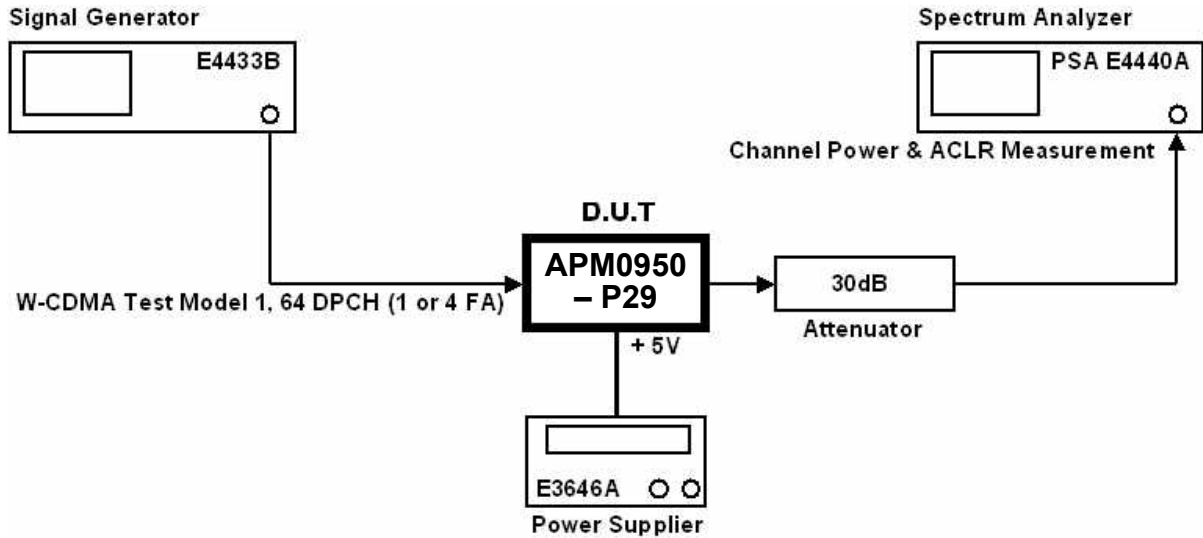
Recommended Soldering Reflow Process



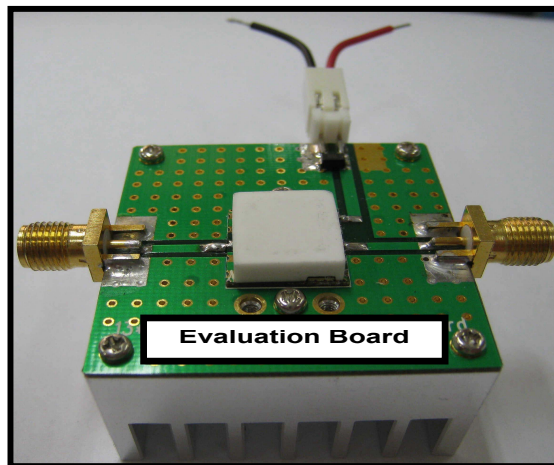
Evaluation Board Layout



Channel Power vs. ACLR Test Configuration



Evaluation Board attached with Heat Sink



** In order to prevent damage of D.U.T (APM-Series) from heating, you must to use a properly sized heat sink for testing a module.*